



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AO5404E N-Channel Enhancement Mode Field Effect Transistor

### General Description

The AO5404E uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications.

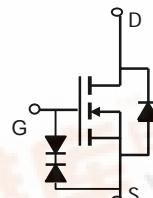
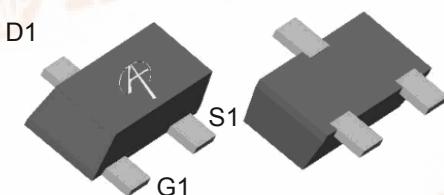
-RoHS compliant

### Features

$V_{DS} (V) = 20V$   
 $I_D = 0.5 A (V_{GS} = 4.5V)$   
 $R_{DS(ON)} < 0.55 \Omega (V_{GS} = 4.5V)$   
 $R_{DS(ON)} < 0.68 \Omega (V_{GS} = 2.5V)$   
 $R_{DS(ON)} < 0.80 \Omega (V_{GS} = 1.8V)$

**ESD PROTECTED!**

SC89-3L



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	10 Sec	Steady State	Units
Drain-Source Voltage	$V_{DS}$	20		V
Gate-Source Voltage	$V_{GS}$	$\pm 8$		V
Continuous Drain Current <sup>A, F</sup> $T_A=25^\circ C$	$I_D$	0.5	0.5	A
$T_A=70^\circ C$	$I_D$	0.5	0.45	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	3		
Power Dissipation <sup>A</sup> $T_A=25^\circ C$	$P_D$	0.38	0.28	W
$T_A=70^\circ C$	$P_D$	0.24	0.18	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150		°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	275	330	°C/W
Maximum Junction-to-Ambient <sup>A</sup> Steady-State		360	450	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	300	350	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm4.5\text{V}$ $V_{DS}=0\text{V}, V_{GS}=\pm8\text{V}$			$\pm 1$ $\pm 100$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.45	0.6	1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	3			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=0.5\text{A}$ $T_J=125^\circ\text{C}$		0.395 0.6	0.55 0.85	$\Omega$
		$V_{GS}=2.5\text{V}, I_D=0.5\text{A}$		0.479	0.68	$\Omega$
		$V_{GS}=1.8\text{V}, I_D=0.3\text{A}$		0.578	0.8	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=0.5\text{A}$		1.5		S
$V_{SD}$	Diode Forward Voltage	$I_S=0.1\text{A}, V_{GS}=0\text{V}$		0.65	1	V
$I_S$	Maximum Body-Diode Continuous Current				0.4	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		35	45	pF
$C_{oss}$	Output Capacitance			8		pF
$C_{rss}$	Reverse Transfer Capacitance			6		pF
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=0.5\text{A}$		0.63	1	nC
$Q_{gs}$	Gate Source Charge			0.08		nC
$Q_{gd}$	Gate Drain Charge			0.16		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=50\Omega, R_{\text{GEN}}=3\Omega$		4.5		ns
$t_r$	Turn-On Rise Time			3.3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			78		ns
$t_f$	Turn-Off Fall Time			32		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=0.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8	10	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=0.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		2		nC

A: The value of  $R_{\text{JJA}}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{JJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{JL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6, 12, 14 are obtained using <300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

F. The maximum current rating is limited by bond-wires

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

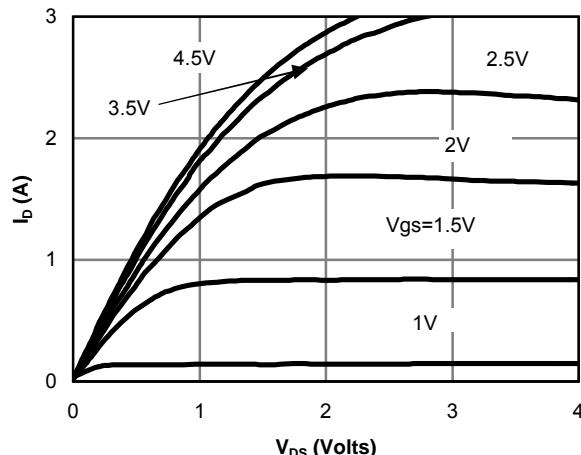


Figure 1: On-Region Characteristics

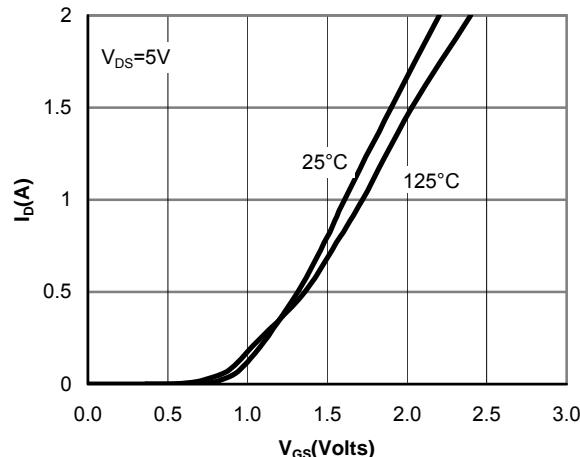


Figure 2: Transfer Characteristics

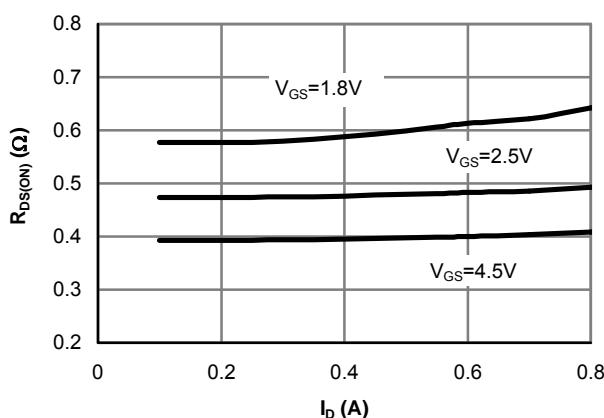


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

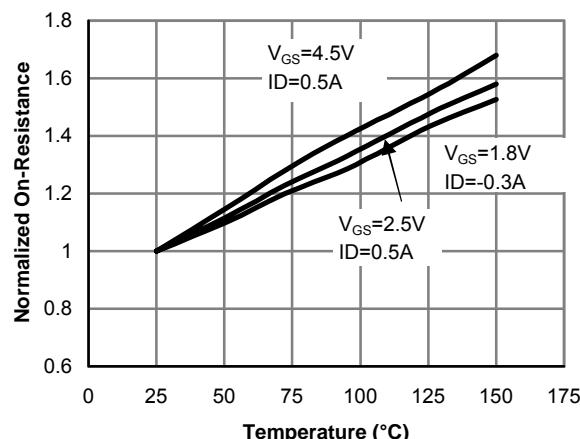


Figure 4: On-Resistance vs. Junction Temperature

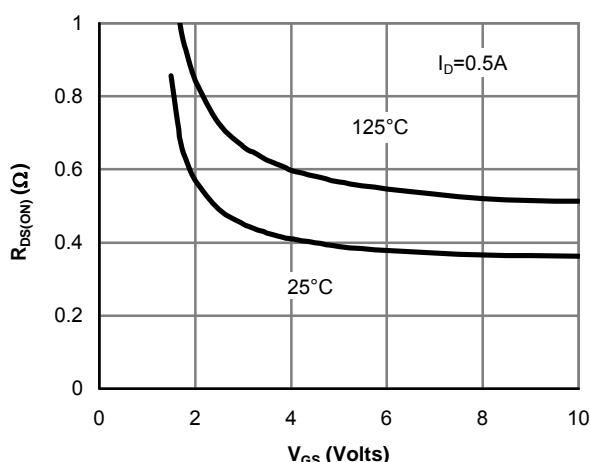


Figure 5: On-Resistance vs. Gate-Source Voltage

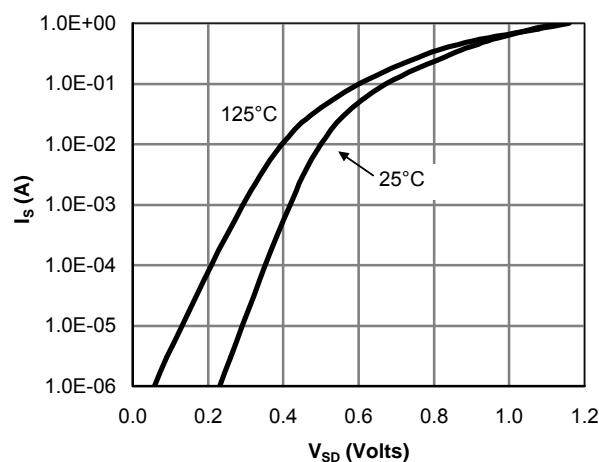


Figure 6: Body-Diode Characteristics

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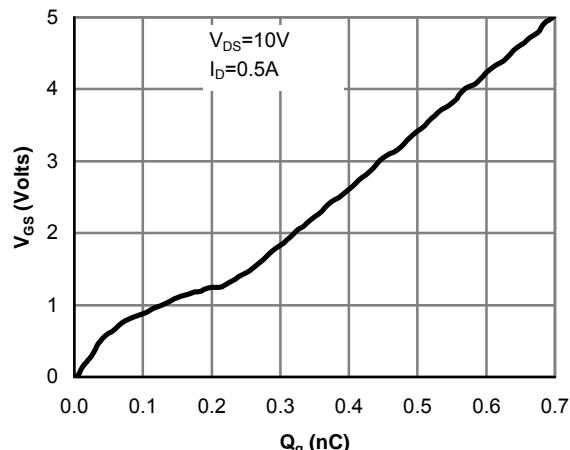


Figure 7: Gate-Charge Characteristics

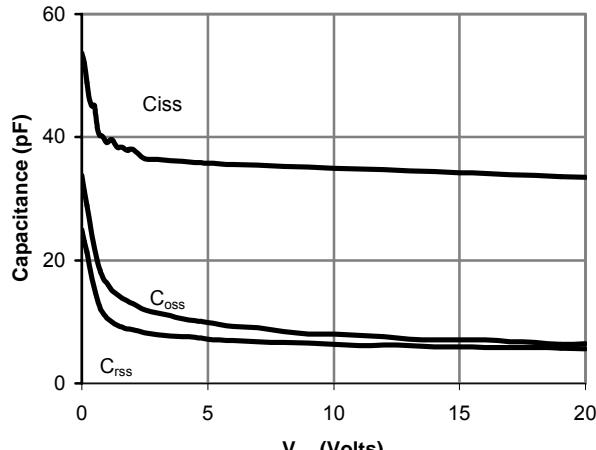


Figure 8: Capacitance Characteristics

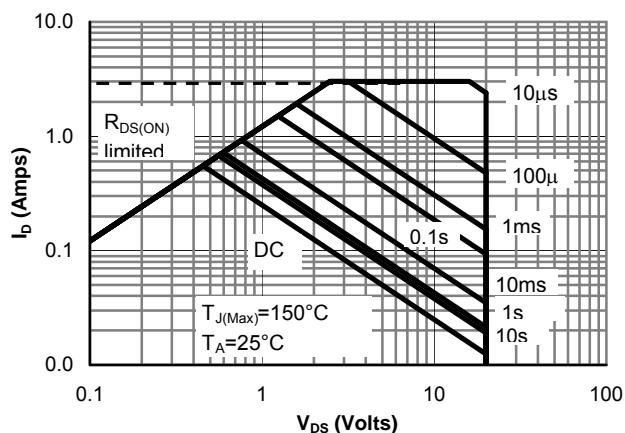


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

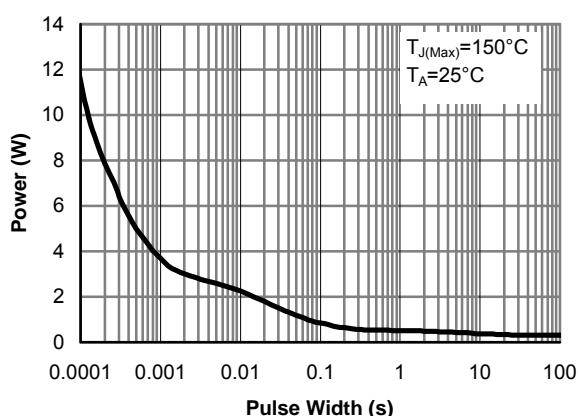


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

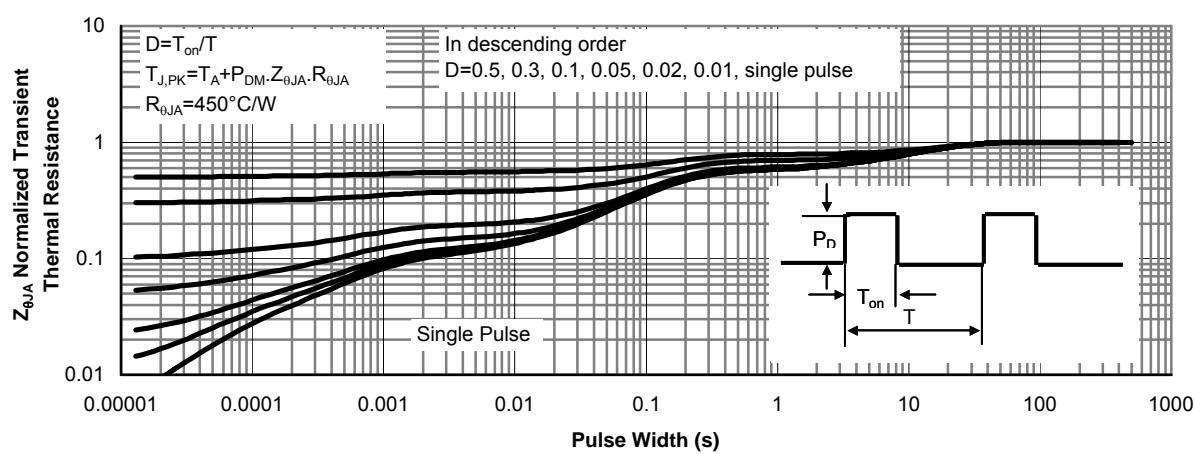


Figure 11: Normalized Maximum Transient Thermal Impedance